

Beam Diagnostics & Instrumentation

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JAI Introductory Lecture, 2024, University of Oxford

2024/11



ISIS Neutron and
Muon Source



Contents

- Recap: Transverse dynamics

Contents

- Recap: Transverse dynamics
- Example: Transverse beam profile

Contents

- Recap: Transverse dynamics
- Example: Transverse beam profile
- Example: Average beam position

Contents

- Recap: Transverse dynamics
- Example: Transverse beam profile
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- Example: Betatron tune

Contents

- Recap: Transverse dynamics
- Example: Transverse beam profile
- Example: Average beam position
- Example: Betatron tune
- Other Diagnostic Systems

Contents

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- Example: Transverse beam profile
- Example: Average beam position
- Example: Betatron tune
- Other Diagnostic Systems
- Conclusion

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- Recap: Transverse dynamics
- Example: Transverse beam profile
- Example: Average beam position
- Example: Betatron tune
- Other Diagnostic Systems
- Conclusion
- Extra: Data Acquisition and Sampling

Recap – Decoupled, Linear Transverse Dynamics

Decoupled

Positions and momenta $(x, p_x), (y, p_y), (z, p_z)$
do not depend on each other.

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E.g. for a drift

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$$p_{x1} = p_{x0}$$

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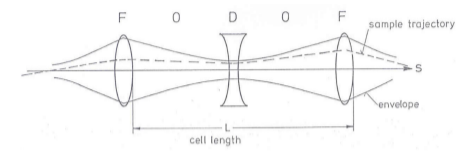
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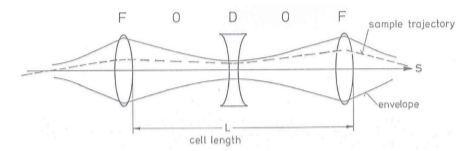
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What properties might we want to know?

Diagnostic Tools

Exactly how to measure a property depends on the details.

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- Electric/ magnetic field sensors
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- Secondary particle detectors (ion chambers, scintillators etc)
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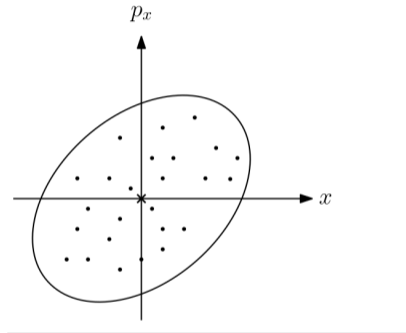
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We process their signals with dedicated electronics to measure the property we're interested in. **We often filter out the information we want at this stage.**

Transverse Profile

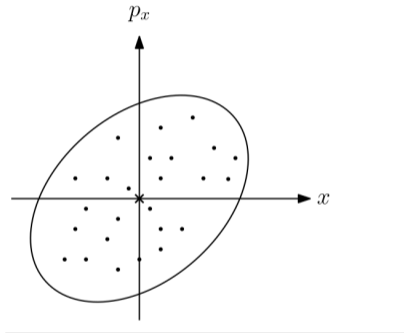
Key point: Diagnostics in the context of phase space.

Probing Transverse Phase Space



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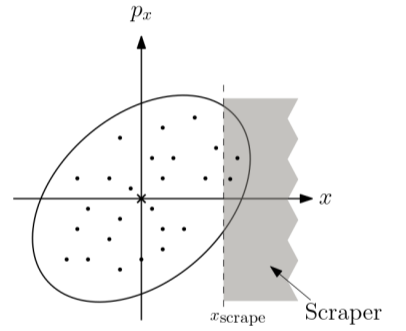
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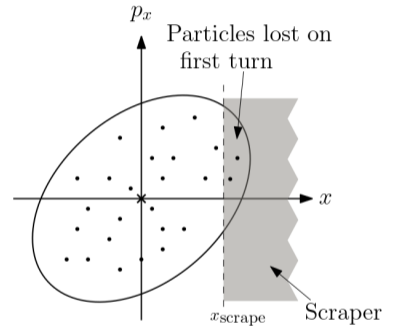
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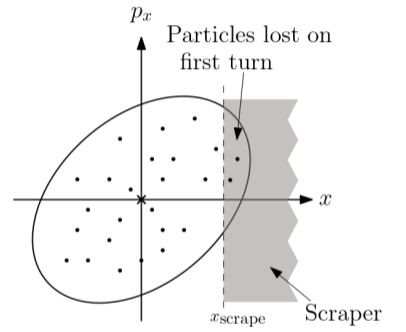


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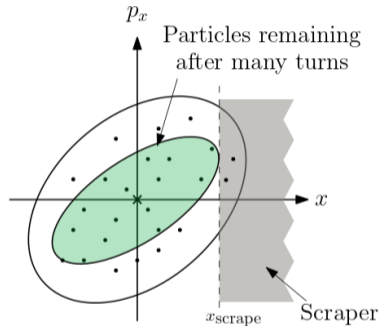


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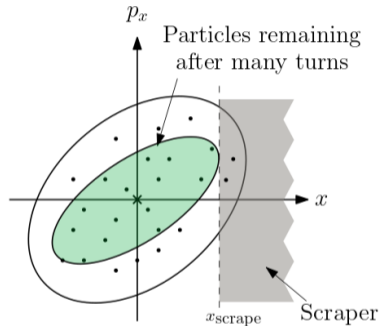
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Distribution of particles with amplitude from:

- Current intercepting scraper
- Number of particles lost/ remaining



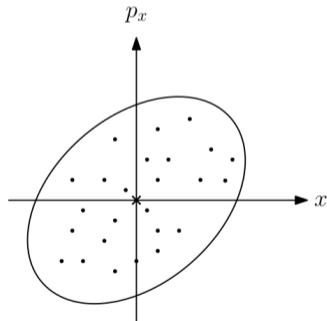
Interceptive Profile Monitors

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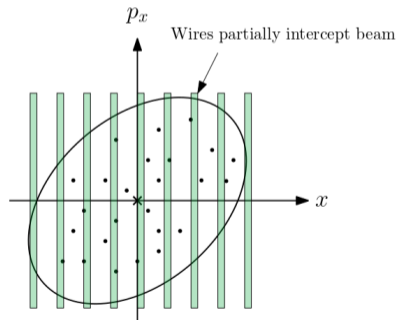


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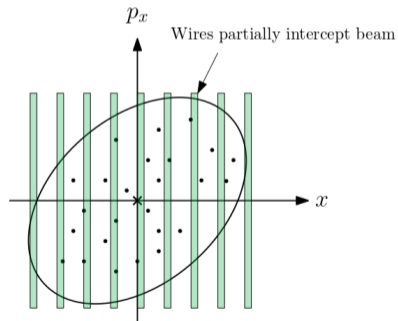
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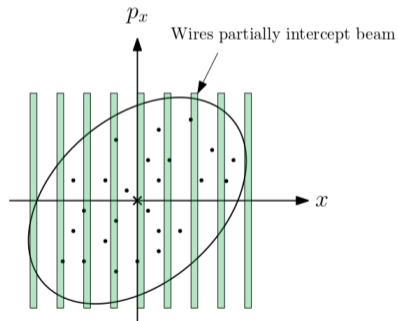
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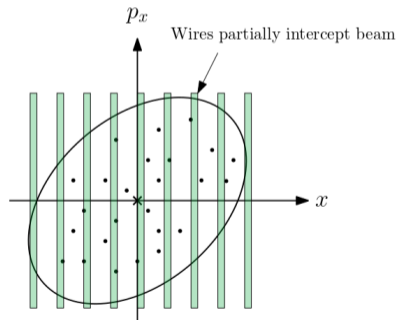
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This method is considered reliable, but

what issues can you see?

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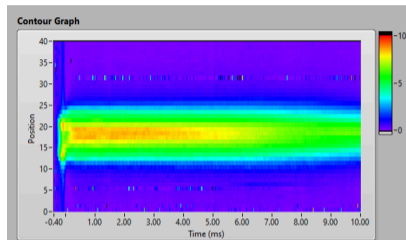
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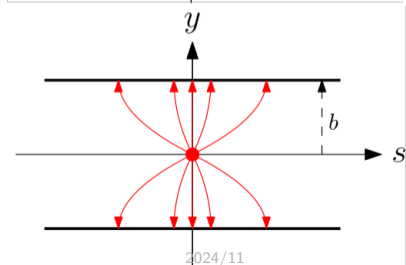
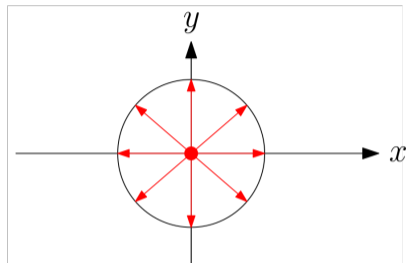
Questions?

Average Transverse Position

Key point: A beam's EM fields provide a wealth of information.

Average Transverse Position

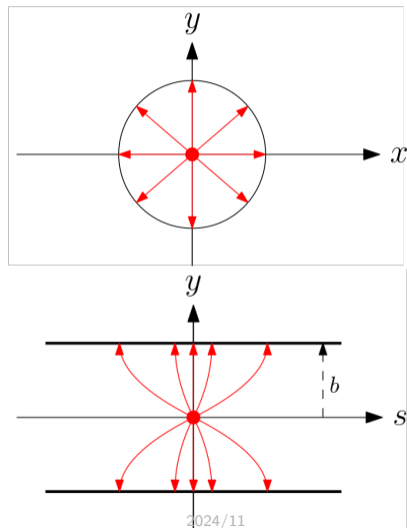
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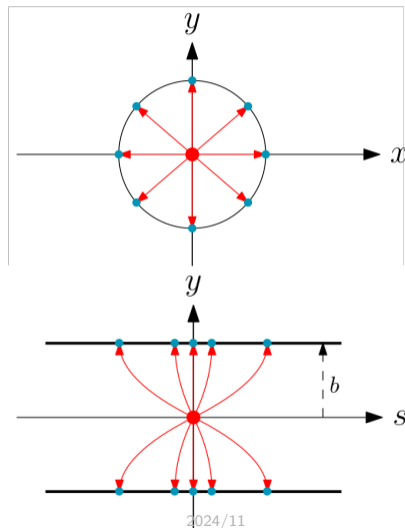


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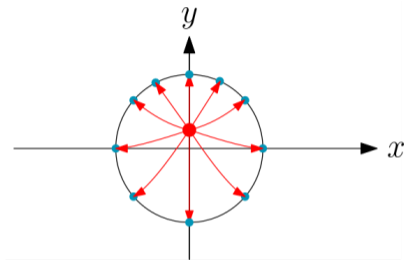


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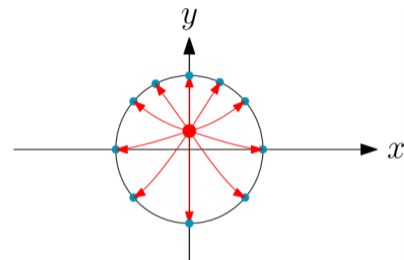
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Understanding the distribution of the image charges or fields, allows us to measure beam position and more, without intercepting it.



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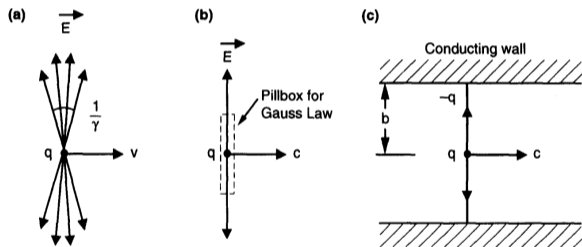


Figure 1.2. Electromagnetic field carried by an ultrarelativistic point charge: (a), (b) in free space; (c) in a perfectly conducting smooth pipe.

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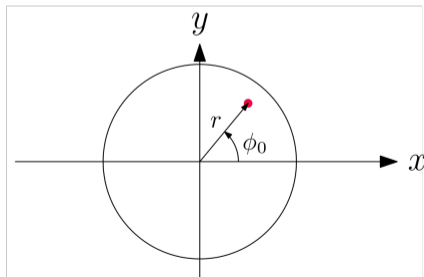
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Beam position monitors are useful for studying longitudinal, and transverse dynamics.

Average Transverse Position

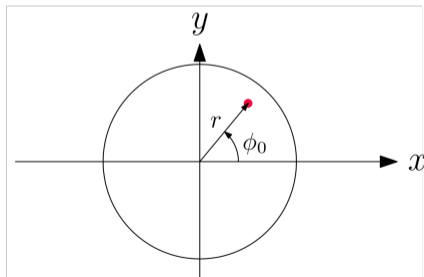
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$$i_w(r, \phi, t) = \frac{-I_b(t)}{2\pi b} \left(1 + 2 \sum_{n=1}^{\infty} \left(\frac{r}{b}\right)^n \cos(n(\phi - \phi_0)) \right)$$

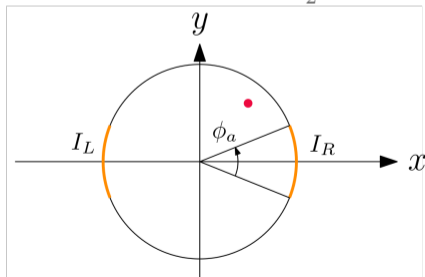


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$$I_R = \int_{\phi=-\phi_a}^{\phi_a} i_w(r, \phi, t) b d\phi = \frac{-I_b(t)}{2\pi} \left(\phi_a + 4 \sum_{n=1}^{\infty} \frac{1}{n} \left(\frac{r}{b}\right)^n \sin\left(\frac{n\phi_a}{2}\right) \cos(n\phi_0) \right)$$

$$I_L = \frac{-I_b(t)}{2\pi} \left(\phi_a + 4 \sum_{n=1}^{\infty} \frac{1}{n} \left(\frac{r}{b}\right)^n (-1)^n \sin\left(\frac{n\phi_a}{2}\right) \cos(n\phi_0) \right)$$

Average Transverse Position

Taking the difference between these currents,

$$\begin{aligned} I_R - I_L &= \frac{-2I_b(t)}{\pi} \sum_{n=1}^{\infty} \frac{1}{n} \left(\frac{r}{b}\right)^n \cos(n\phi_0) \sin\left(\frac{n\phi_a}{2}\right) (1 - (-1)^n) \\ &= \frac{-4I_b(t)}{\pi} \frac{r}{b} \cos(\phi_0) \sin\left(\frac{\phi_a}{2}\right) + A_3 \left(\frac{r}{b}\right)^3 + A_5 \left(\frac{r}{b}\right)^5 + \dots \end{aligned}$$

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For now assume $\phi_0 = 0$ so we are only discussing horizontal position.

Average Transverse Position

In theory, we could use this **difference** signal

$$I_R - I_L \approx \frac{-4I_b(t)}{\pi} \frac{r}{b} \sin\left(\frac{\phi_a}{2}\right),$$

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It would be preferable to remove this dependence. Consider the **sum** signal

$$I_R + I_L = \frac{-I_b(t)}{2\pi} \left(2\phi_a + 4 \sum_{n=1}^{\infty} \frac{1}{n} \left(\frac{r}{b}\right)^n \sin\left(\frac{n\phi_a}{2}\right) (1 + (-1)^n) \right) \approx -I_b(t) \frac{\phi_a}{\pi}$$

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We often use the ratio, because this is independent of $I_b(t)$

$$\frac{I_R - I_L}{I_R + I_L} \approx \frac{4}{\phi_a} \frac{r}{b} \sin\left(\frac{\phi_a}{2}\right)$$

Transverse Position Sensors

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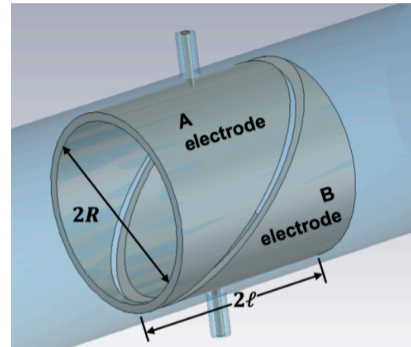
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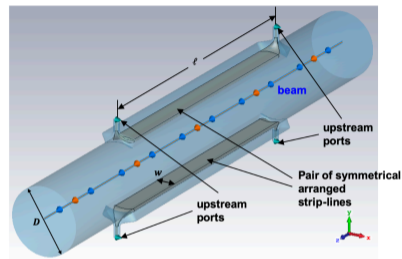
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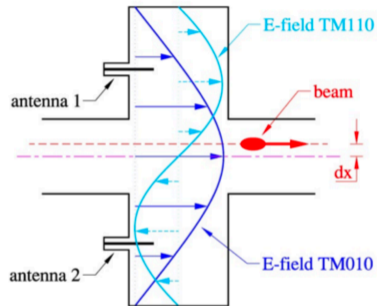
- capacitive pickups
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Transverse Position Sensors

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Device suitability depends on bunch structure.

Split-plate BPMs popular for large bunches, and buttons are common at light sources.

Questions?

Betatron Tune

Key point 1: A beam can be made to reveal its properties.

Key point 2: Fourier analysis is very useful.

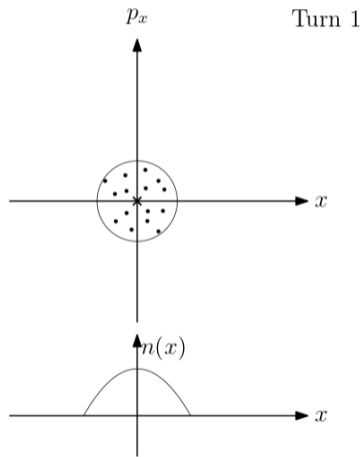
Betatron Tune

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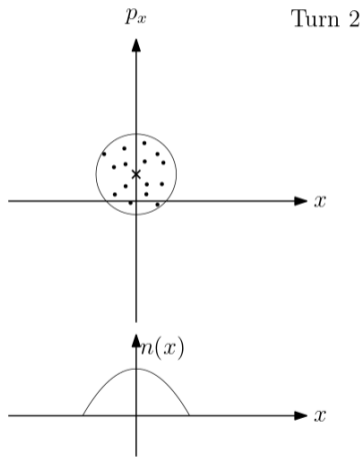


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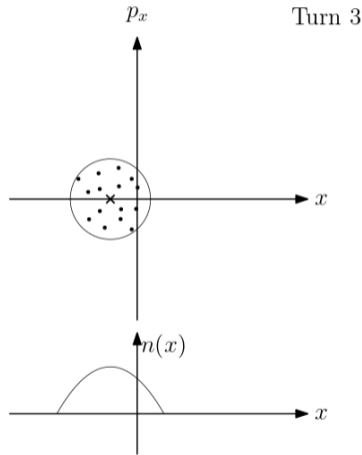


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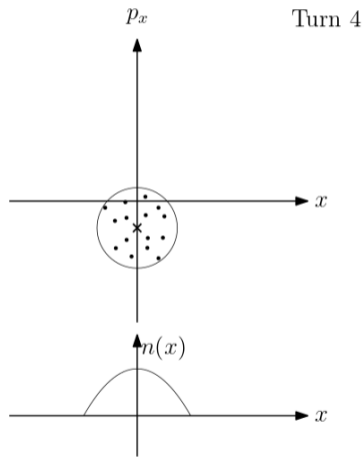


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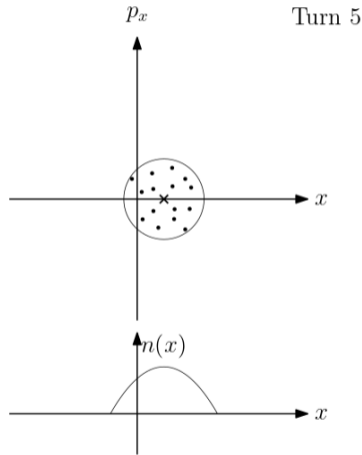


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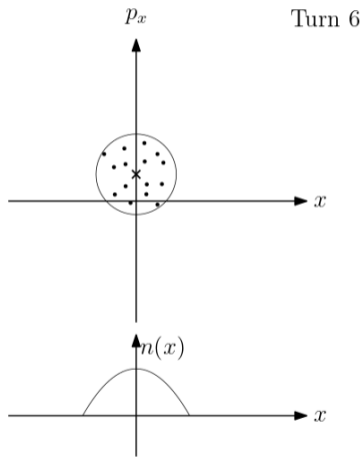


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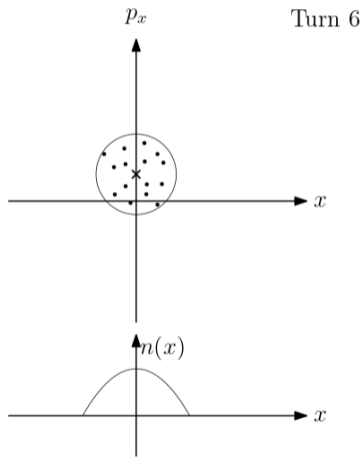
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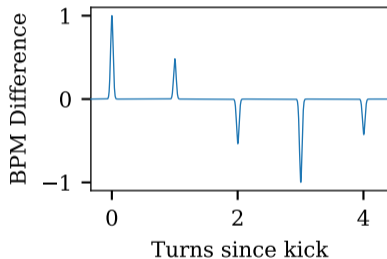
A common technique to measure tune is to use a kicker to increase p_x on a single turn, which will cause the beam's average position to oscillate.

Oscillation frequency gives non-integer tune.



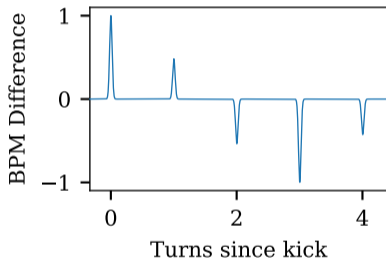
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An idealised BPM difference signal will resemble a beam pulse, with its amplitude modulated by transverse offset. For non-integer tunes, amplitude changes on each turn.



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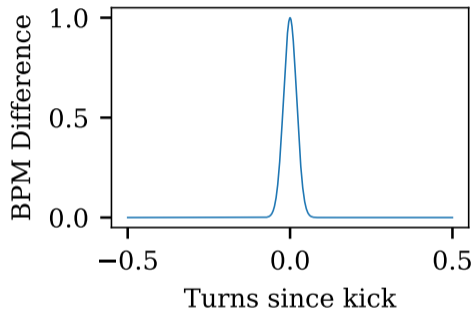
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To understand how to obtain the tune, let's write down an ideal BPM difference signal.

Betatron Tune

If $y(t)$ is the longitudinal charge distribution of a bunch, assume signal will resemble $y(t)$.

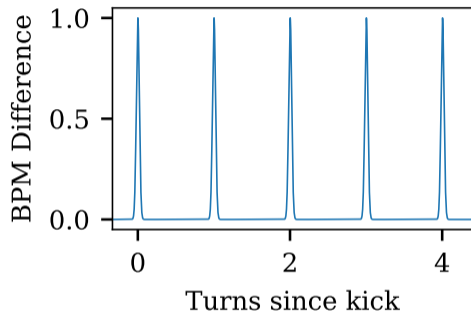


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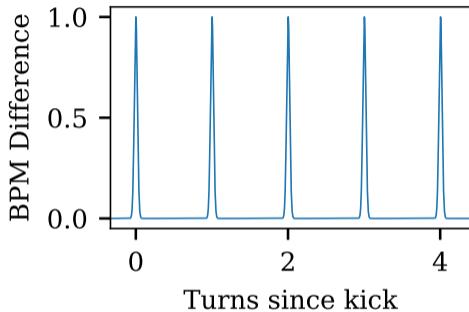


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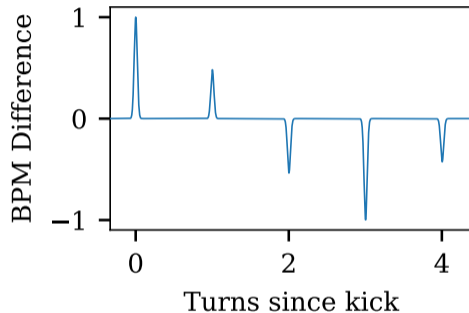
where $*$ is a convolution

Betatron Tune

To include the transverse oscillations, we write

$$V(t) = y(t) * A \cos(\omega_{\beta} t) \sum_{n=-\infty}^{\infty} \delta(t - nT_p),$$

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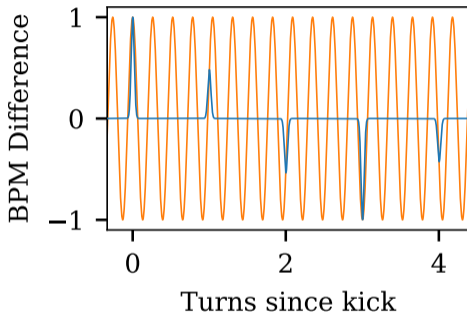
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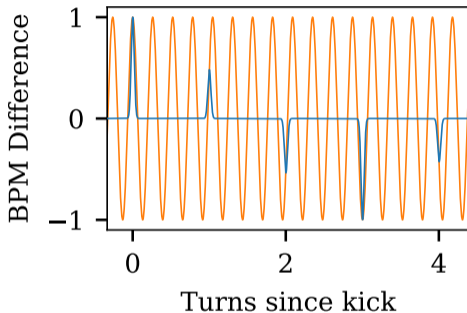
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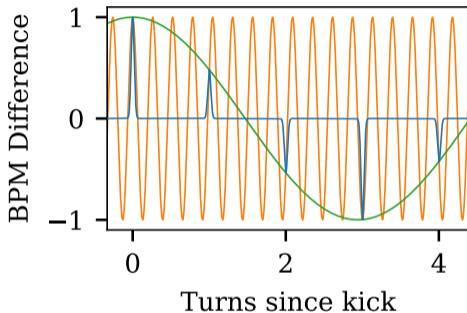
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and its inverse $\mathcal{F}(h(t)k(t)) = \frac{1}{2\pi} \mathcal{F}(h(t)) * \mathcal{F}(k(t))$, plus the important result

$$\mathcal{F} \left(\sum_{n=-\infty}^{\infty} \delta(t - nT_p) \right) = \frac{2\pi}{T_p} \sum_{n=-\infty}^{\infty} \delta \left(\omega - n \frac{2\pi}{T_p} \right).$$

The result is

$$\tilde{V}(\omega) = \frac{A}{2} \mathcal{F}[y(t)] \omega_0 \sum_{n=-\infty}^{\infty} [\delta(\omega - n\omega_0 - \omega_\beta) + \delta(\omega - n\omega_0 + \omega_\beta)]$$

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We can't distinguish the integer part of the tune from a single monitor, because $\omega_\beta = \omega_0(m + q)$ where m is an integer. The delta-functions become $\delta(\omega - (n \pm m)\omega_0 \pm q\omega_0)$. Since this appears in an infinite sum, we can't distinguish between n and $n \pm m$.

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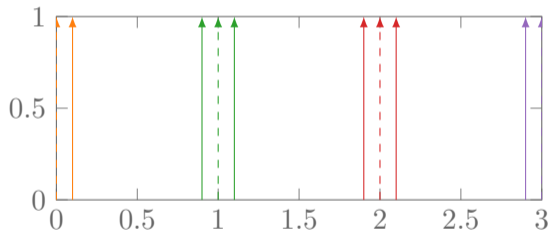
The quantity of interest, q can then be found by measuring the difference in frequency between the **revolution harmonics** and the **sidebands** and dividing by $f_0 = \frac{1}{T_p}$

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We can also get an intuitive picture of why it is that we can only measure up to the half-integer. Plot $\tilde{V}(\omega)$ for increasing values of fractional tune:

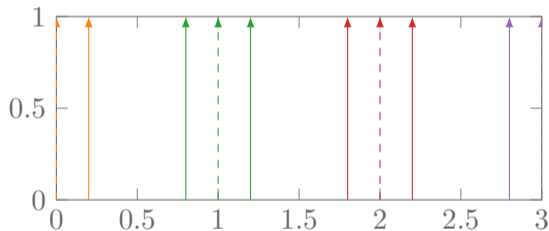
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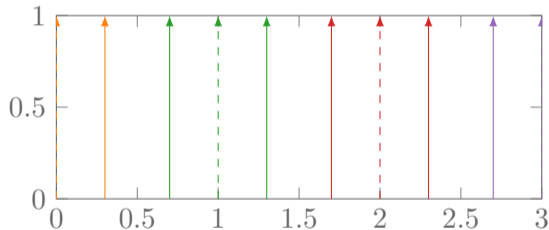
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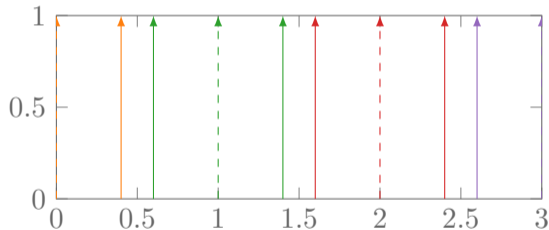
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We can also get an intuitive picture of why it is that we can only measure up to the half-integer. Plot $\tilde{V}(\omega)$ for increasing values of fractional tune: $q = 0.3$.



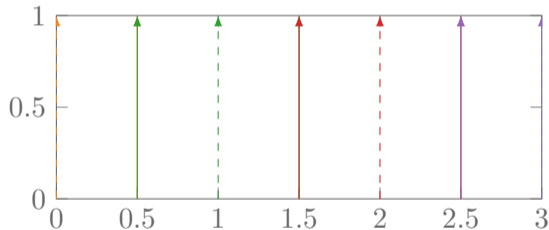
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We can also get an intuitive picture of why it is that we can only measure up to the half-integer. Plot $\tilde{V}(\omega)$ for increasing values of fractional tune: $q = 0.4$.



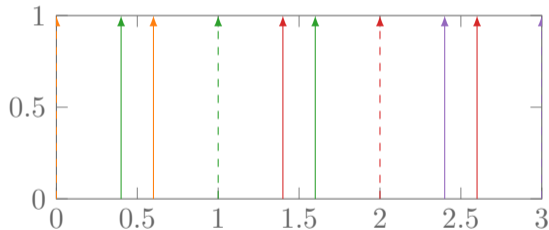
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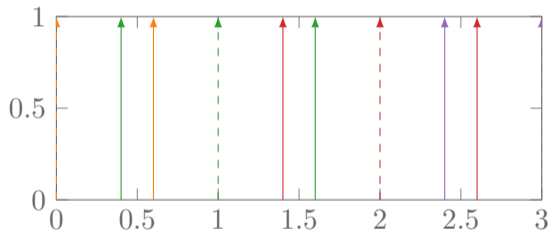
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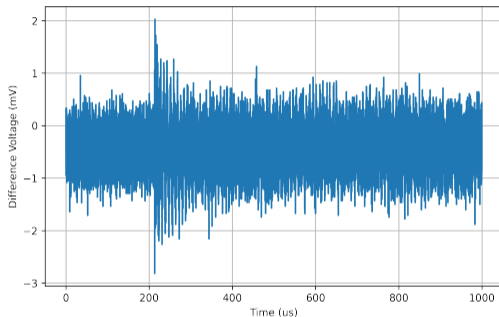
We can also get an intuitive picture of why it is that we can only measure up to the half-integer. Plot $\tilde{V}(\omega)$ for increasing values of fractional tune: $q = 0.6$.



Sidebands have swapped places! **We can't know if $q = 0.4$ or $1 - 0.4 = 0.6$.**

Tune Measurement Example

This is an example BPM difference signal during a tune measurement on the ISIS synchrotron. A kick was applied at around 200 μs .

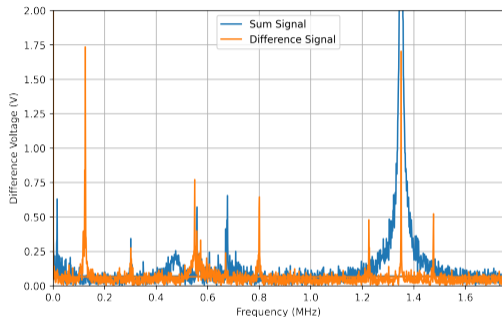


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Use an FFT to obtain a spectra of this signal.



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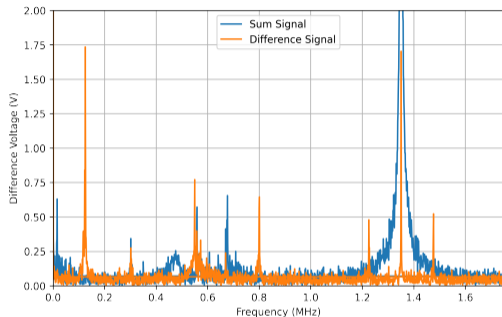
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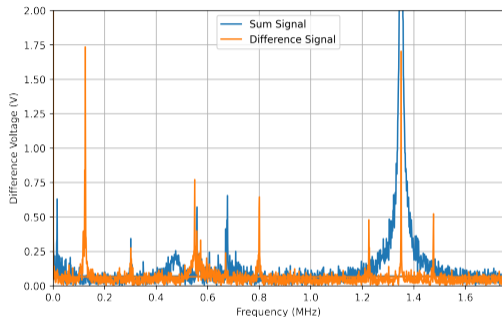
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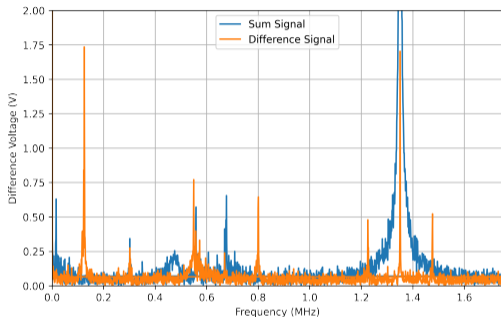
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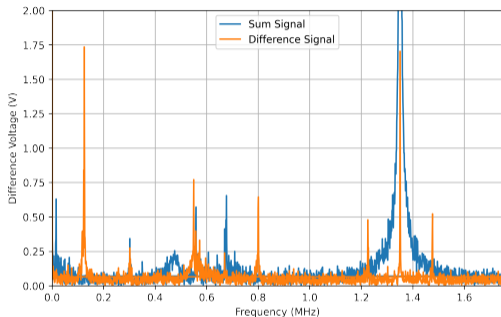
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Fractional tune is either 0.19 or 0.81.

Questions?

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But there are two systems I haven't mentioned which are very important, and I would like to mention them, even without much detail.

Like some of the more detailed examples, they can be used in combination with other equipment and techniques to measure a range of beam and machine parameters.

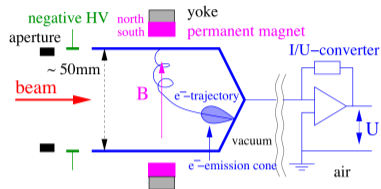
Beam Current Monitors

Measure the number of accelerated particles. [5, 6]

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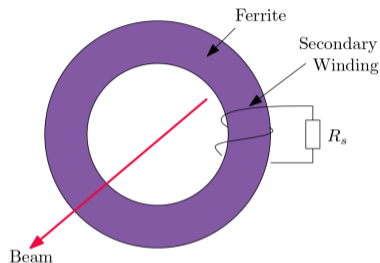


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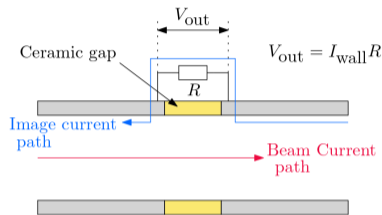
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Wall current monitors generate a voltage from the image current flowing in the vacuum vessel.



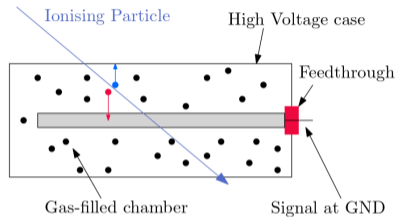
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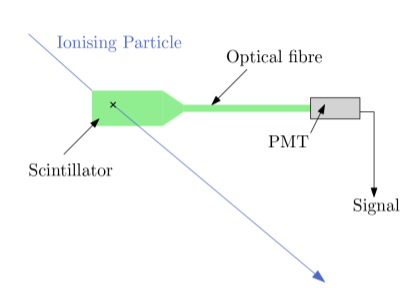


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In a scintillator BLM, light is generated when an incoming particle passes through its sensitive volume. The light signal is converted into an electrical signal.



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- Sometimes the quantity of interest can be obtained **directly from the spectra**.
- Please review some of the **excellent references** for more detail.

References

- [1] R. E. Shafer. *Beam position monitoring*. DOI: [10.1063/1.39710](https://doi.org/10.1063/1.39710).
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Extra: Data Acquisition and Sampling

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Whatever diagnostics you use, you will be digitising analogue signals with an ADC [8]. This procedure, whilst very common, is a critical step in the measurement process. There are a few things that it is good to be aware of.

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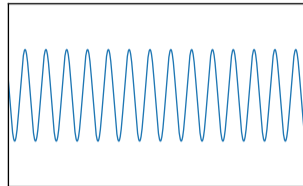
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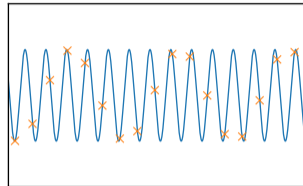
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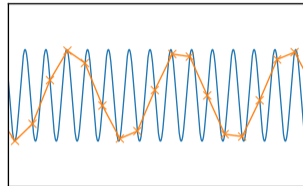
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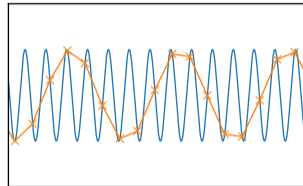


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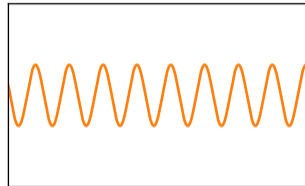
After a signal has been sampled, there is no general correction method. **Must be considered in advance!**



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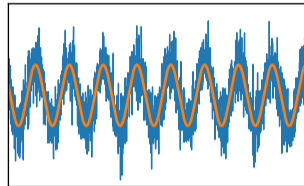
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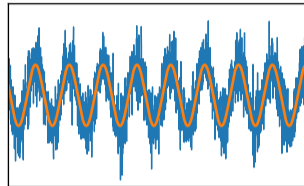


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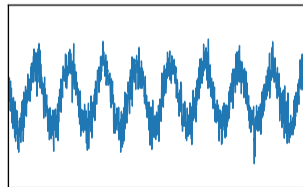
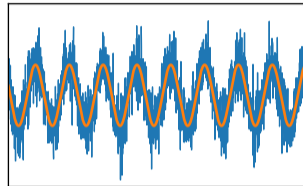
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